



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Astute Electronics Inc.
500 Center Ridge Drive, Suite 600
Austin, TX 78753

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

A handwritten signature in black ink, appearing to be 'J. Stine', is positioned above a horizontal line.

Jason Stine, Vice President

Expiry Date: 23 January 2026

Certificate Number: AT-3278



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Astute Electronics Inc.

500 Center Ridge Drive, Suite 600
Austin, TX 78753

Michael Flores michael.flores@astutegroup.com
515-228-7563

TESTING

Valid to: **January 23, 2026**

Certificate Number: **AT-3278**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to the **Astute Electronics Inc.** to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

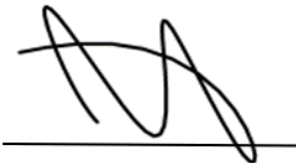
Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
External Visual Inspection (EVI)	AS6171/2 (Methods A & B) AS6081 4.2.6.4.1 & 4.2.6.4.2 IDEA-STD-1010 10.1 & 10.2	Electrical, Electronic and Electromechanical (EEE) Components	Microscopes Scale
Dimensional Inspection	AS6171/2 (Method E) AS6081 4.2.6.4.2.2 IDEA-STD-1010 10.3 & 10.3.3	Electrical, Electronic and Electromechanical (EEE) Components	Keyence LM-1100 Digital Calipers
Radiographic (X-Ray) Inspection	AS6171/5 AS6081 4.2.6.4.4 IDEA-STD-1010 11.4	Electrical, Electronic and Electromechanical (EEE) Components	Creative Electron Fusion R
X-Ray Fluorescence (XRF) Inspection	AS6171/3 AS6081 4.2.6.4.5 IDEA-STD-1010 11.3	Electrical, Electronic and Electromechanical (EEE) Components	Fischer XDAL Spectrometer XRF System

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Resistance to Solvents (Remarking and Resurfacing)	AS6171/2 (Methods C & D) AS6081 4.2.6.4.3 IDEA-STD-101010.3.2	Electrical, Electronic and Electromechanical (EEE) Components	Multiple Solvents X-Acto Blade
Solderability Test	J-STD-002	Electrical, Electronic and Electromechanical (EEE) Components	Hentec Pulsar Solderability Test System
Heated Solvent Tests	AS6171/2 (Method D) AS6081 4.2.6.4.3 IDEA-STD-1010 11.6	Electrical, Electronic and Electromechanical (EEE) Components	Hot Plate Digital Thermometer Multiple Solvents
Delid/Decapsulation Physical Analysis (DDPA)	AS6171/4 AS6081 4.2.6.4.6 IDEA-STD-1010 11.7	Electrical, Electronic and Electromechanical (EEE) Components	Tabletop Furnace Hot Plate Chemicals Microscopes

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-3278.



Jason Stine, Vice President